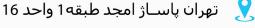






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Data sheet acquired from Harris Semiconductor SCHS205A

CD74HC4049, CD74HC4050

High-Speed CMOS Logic Hex Buffers, Inverting and Non-Inverting

February 1998 - Revised June 1999

Features

- Typical Propagation Delay: 6ns at V_{CC} = 5V, C_L = 15pF, T_A = 25°C
- High-to-Low Voltage Level Converter for up to V_I = 16V
- Fanout (Over Temperature Range)
- Wide Operating Temperature Range . . . –55°C to 125°C
- Balanced Propagation Delay and Transition Times
- Significant Power Reduction Compared to LSTTL Logic ICs
- HC Types
 - 2V to 6V Operation
 - High Noise Immunity: N_{IL} = 30%, N_{IH} = 30% of V_{CC} at V_{CC} = 5V

Description

The CD74HC4049 and CD74HC4050 are fabricated with high-speed silicon gate technology. They have a modified input protection structure that enables these parts to be used as logic level translators which convert high-level logic to a low-level logic while operating off the low-level logic supply. For example, 15-V input pulse levels can be down-converted to 0-V to 5-V logic levels. The modified input protection structure protects the input from negative electrostatic discharge. These parts also can be used as simple buffers or inverters without level translation. The CD74HC4049 and CD74HC4050 are enhanced versions of equivalent CMOS types.

Ordering Information

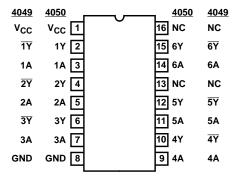
PART NUMBER	TEMP. RANGE (°C)	PACKAGE	PKG. NO.		
CD74HC4049E	-55 to 125	16 Ld PDIP	E16.3		
CD74HC4050E	-55 to 125	16 Ld PDIP	E16.3		
CD74HC4049M	-55 to 125	16 Ld SOIC	M16.15		
CD74HC4050M	-55 to 125	16 Ld SOIC	M16.15		
CD74HC4050PW	-55 to 125	16 Ld TSSOP			

NOTES:

- When ordering, use the entire part number. Add the suffix 96 to the M suffix or the R suffix to the PW package to obtain the variant in the tape and reel.
- Wafer and die is available which meets all electrical specifications. Please contact your local sales office or customer service for ordering information.

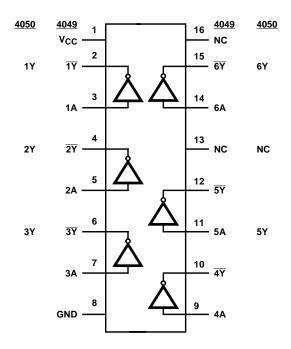
Pinout

CD74HC4049, CD74HC4050 (PDIP, SOIC, TSSOP) TOP VIEW



CD74HC4049, CD74HC4050

Functional Diagram

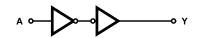


Logic Diagrams

HC4049

 $A \longleftarrow \bigvee \overline{Y}$

HC4050



CD74HC4049, CD74HC4050

Absolute Maximum Ratings

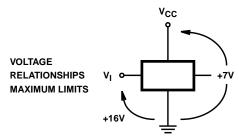
DC Supply Voltage, V _{CC}
DC Input Diode Current, I _{IK}
For $V_I < -0.5V$ or $V_I > V_{CC} + 0.5V$ ±20mA
DC Output Diode Current, I _{OK}
For $V_O < -0.5V$ or $V_O > V_{CC} + 0.5V$
DC Output Source or Sink Current per Output Pin, IO
For $V_O > -0.5V$ or $V_O < V_{CC} + 0.5V$
DC V _{CC} or Ground Current, I _{CC or} I _{GND}

Operating Conditions

Temperature Range (T _A)–55°C to 125°C
Supply Voltage Range, V _{CC}
HC Types2V to 6V
HCT Types
DC Input or Output Voltage, V _I , V _O 0V to V _{CC}
Input Rise and Fall Time
2V
4.5V 500ns (Max)
6V

Thermal Information

Thermal Resistance (Typical, Note 3)	θ _{JA} (ºC/W)
PDIP Package	. 78
SOIC Package	
TSSOP Package	. 149
Maximum Junction Temperature (Hermetic Package or	Die) 175°C
Maximum Junction Temperature (Plastic Package) .	
Maximum Storage Temperature Range	-65°C to 150°C
Maximum Lead Temperature (Soldering 10s)	300°C
(SOIC - Lead Tips Only)	



CAUTION: Stresses above those listed in "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress only rating and operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied.

NOTE:

3. $\theta_{\mbox{\scriptsize JA}}$ is measured with the component mounted on an evaluation PC board in free air.

DC Electrical Specifications

		TE: CONDI		v _{cc}	25°C			–40°C TO 85°C		–55°C TO 125°C		
PARAMETER	SYMBOL	V _I (V)	I _O (mA)	(V)	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNITS
HC TYPES		-			-	-		-	-		-	
High Level Input	V _{IH}	-	-	2	1.5	-	-	1.5	-	1.5	-	V
Voltage				4.5	3.15	-	-	3.15	-	3.15	-	V
				6	4.2	-	-	4.2	-	4.2	-	V
Low Level Input	V _{IL}	-	-	2	-	-	0.5	-	0.5	·	0.5	V
Voltage				4.5	-	-	1.35	-	1.35	-	1.35	V
				6	-	-	1.8	-	1.8	-	1.8	V
High Level Output	V _{OH}	V _{IH} or V _{IL}	-0.02	2	1.9	-	-	1.9	-	1.9	-	V
Voltage CMOS Loads			-0.02	4.5	4.4	-	-	4.4	-	4.4	-	V
Omeo Loado			-0.02	6	5.9	-	-	5.9	-	5.9	-	V
High Level Output	1		-4	4.5	3.98	-	-	3.84	-	3.7	-	V
Voltage TTL Loads			-5.2	6	5.48	-	-	5.34	-	5.2	-	V
Low Level Output Voltage CMOS Loads	V _{OL}	V _{IH} or V _{IL}	0.02	2	-	-	0.1	-	0.1	-	0.1	V
			0.02	4.5	-	-	0.1	-	0.1	-	0.1	V
			0.02	6	-	-	0.1	-	0.1	-	0.1	V
Low Level Output Voltage TTL Loads	1		4	4.5	-	-	0.26	-	0.33	-	0.4	V
			5.2	6	-	-	0.26	-	0.33	-	0.4	V
Input Leakage Current	lı	V _{CC} or GND	-	6	-	-	±0.1	-	±1	-	±1	μА
		15	-	6	-	-	±0.5	-	±5	-	±5	
Quiescent Device Current	I _{CC}	V _{CC} or GND	0	6	-	-	2	-	20	-	40	μА

NOTE: For dual-supply systems theorectical worst case ($V_I = 2.4V$, $V_{CC} = 5.5V$) specification is 1.8mA.

CD74HC4049, CD74HC4050

Switching Specifications Input t_r , t_f = 6ns

		TEST		25°C		–40°C TO 85°C		–55°C TO 125°C			
PARAMETER	SYMBOL	CONDITIONS	V _{CC} (V)	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNITS
HC TYPES										_	
Propagation Delay,	t _{PLH} , t _{PHL}	$C_L = 50pF$	2	-	-	85	-	105	-	130	ns
nA to nY HC4049 nA to nY HC4050			4.5	-	-	17	-	21	-	26	ns
1000			6	-	-	14	-	18	-	22	ns
		C _L = 15pF	5	-	6	-	-	-	-	-	ns
Transition Times (Figure 1)	t _{TLH} , t _{THL}	C _L = 50pF	2	-	-	75	-	95	-	110	ns
			4.5	-	-	15	-	19	-	22	ns
			6	-	-	13	-	16	-	19	ns
Input Capacitance	Cl	-	-	-	-	10	-	10	-	10	pF
Power Dissipation Capacitance (Notes 4, 5)	C _{PD}	-	5	-	35	-	-	-	-	-	pF

NOTES:

- 4. C_{PD} is used to determine the dynamic power consumption, per gate.
- 5. $P_D = V_{CC}^2 f_i (C_{PD} + C_L)$ where f_i = Input Frequency, C_L = Output Load Capacitance, V_{CC} = Supply Voltage.

Test Circuit and Waveform

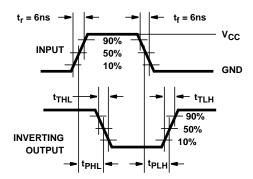


FIGURE 1. HC AND HCU TRANSITION TIMES AND PROPAGATION DELAY TIMES, COMBINATION LOGIC

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